# MOSFET - Single N-Channel 80 V, 21 m $\Omega$ , 24 A

# NTTFD021N08C

# **General Description**

This device includes two specialized N-Channel MOSFETs in a dual package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q2) and synchronous (Q1) have been designed to provide optimal power efficiency.

#### **Features**

Q1: N-Channel

- Max  $r_{DS(on)} = 21 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 7.8 \text{ A}$
- Max  $r_{DS(on)}$  = 55 m $\Omega$  at  $V_{GS}$  = 6 V,  $I_D$  = 3.9 A Q2: N-Channel
- Max  $r_{DS(on)} = 21 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 7.8 \text{ A}$
- Max  $r_{DS(on)} = 55 \text{ m}\Omega$  at  $V_{GS} = 6 \text{ V}$ ,  $I_D = 3.9 \text{ A}$
- Low Inductance Packaging Shortens Rise/Fall Times, Resulting in Lower Switching Losses
- RoHS Compliant

# **Applications**

- Computing
- Communications
- General Purpose Point of Load

# **PIN DESCRIPTION**

Pin	Name	Description
1, 11, 12	GND (LSS)	Low Side Source
2	LSG	Low Side Gate
3, 4, 5, 6	V + (HSD)	High Side Drain
7	HSG	High Side Gate
8, 9, 10	SW	Switching Node, Low Side Drain



# ON Semiconductor®

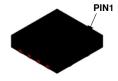
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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
80 V	21 mΩ @ 10 V	24 A
	55 mΩ @ 6 V	247

# **ELECTRICAL CONNECTION**

GND	1]	12		10	sw	GND	1)- 🔠	10 SW
LSG	2	GND	]	9	sw	LSG	2	-[9] SW
V+	3		7	8	sw	V+	37 (1)	[8] SW
V+	4	5	6	7	HSG	ì V+	4]	—[₹ HSG

**Dual N-Channel MOSFET** 





Ton

Bottom

Power Clip 33 Symmetric (WQFN12) CASE 510CJ

# **MARKING DIAGRAM**

O D021 AYWWZZ

D021 = Specific Device Code
A = Assembly Plant Code
Y = Numeric Year Code
WW = Work Week Code
ZZ = Assembly Lot Code

#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 2 of this data sheet.

# ORDERING INFORMATION AND PACKAGE MARKING

Device	Marking	Package	Shipping <sup>†</sup>
NTTFD021N08C	D021	WQFN12 (Pb-Free)	3000 Units/ Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

# **MOSFET MAXIMUM RATINGS** ( $T_A = 25$ °C, Unless otherwise specified)

Symbol		Parame	eter		Q1	Q2	Units
V <sub>DS</sub>	Drain-to-Source Volta	rain-to-Source Voltage					V
$V_{GS}$	Gate-to-Source Voltag	е			±20	±20	V
I <sub>D</sub>	Drain Current -C	ontinuous	T <sub>C</sub> = 25°C	(Note 4)	24	24	Α
	-C	ontinuous	T <sub>C</sub> = 100°C	(Note 4)	15	15	
	-C	ontinuous	T <sub>A</sub> = 25°C		6 (Note 1a)	6 (Note 1b)	
	_F	ulsed	T <sub>A</sub> = 25°C		349	349	
E <sub>AS</sub>	Single Pulse Avalanche	Energy (L = 1 mH,	I <sub>L(pk)</sub> = 7.9 A)	(Note 3)	31	31	mJ
$P_{D}$	Power Dissipation for S	ingle Operation	T <sub>C</sub> = 25°C		26	26	W
	Power Dissipation for S	ingle Operation	T <sub>A</sub> = 25°C		1.7 (Note 1a)	1.7 (Note 1b)	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			–55 to	+150	°C	
TL	Lead Temperature for S	Soldering Purposes	(1/8" from case for 10 s)		260	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

# THERMAL CHARACTERISTICS

Symbol	Parameter	Q1	Q2	Units
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	4.8	4.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	70 (Note 1a)	70 (Note 1b)	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	135 (Note 1c)	135 (Note 1c)	

# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units		
OFF CHAR	OFF CHARACTERISTICS								
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0 \ V$	Q1	80			V		
		$I_D = 250 \mu A, V_{GS} = 0 V$	Q2	80					
$\Delta BV_{DSS}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, referenced to 25°C	Q1		68.2		mV/°C		
$\Delta T_{J}$		I <sub>D</sub> = 250 μA, referenced to 25°C	Q2		68.2				
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V	Q1			1	μΑ		
		V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V	Q2			1			
I <sub>GSS</sub>	Gate-to-Source Leakage Current,	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	Q1			±100	nA		
	Forward	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V	Q2			±100			

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

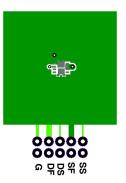
Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
ON CHAR	ACTERISTICS						
V <sub>GS(th)</sub>	Gate-to-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 44 \mu A$	Q1	2	2.8	4	V
		$V_{GS} = V_{DS}$ , $I_D = 44 \mu A$	Q2	2	2.8	4	
$\Delta V_{GS(th)}$	Gate-to-Source Threshold Voltage	$I_D$ = 44 $\mu$ A, referenced to 25°C	Q1		-8.86		mV/°C
$\Delta T_{J}$	Temperature Coefficient	$I_D = 44 \mu A$ , referenced to $25^{\circ}C$	Q2		-8.86		
r <sub>DS(on)</sub>	Drain-to-Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 7.8 A	Q1		16.4	21	mΩ
		V <sub>GS</sub> = 6 V, I <sub>D</sub> = 3.9 A			26	55	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 7.8 A, T <sub>J</sub> = 125°C			28.9		
r <sub>DS(on)</sub>	Drain-to-Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 7.8 \text{ A}$	Q2		16.4	21	mΩ
		$V_{GS} = 6 \text{ V}, I_D = 3.9 \text{ A}$			26	55	
		$V_{GS} = 10 \text{ V}, I_D = 7.8 \text{ A},$ $T_J = 125^{\circ}\text{C}$			28.9		
9FS	Forward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 7.8 A	Q1		227		S
		V <sub>DS</sub> = 5 V, I <sub>D</sub> = 7.8 A	Q2		227		
YNAMIC	CHARACTERISTICS						
C <sub>ISS</sub>	Input Capacitance	Q1:	Q1		572		pF
		$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ Mhz}$	Q2		572		
Coss	Output Capacitance	<b>-</b> Q2:	Q1		227		pF
		$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	Q2		227		
C <sub>RSS</sub>	Reverse Transfer Capacitance		Q1		11		pF
			Q2		11		1
$R_{G}$	Gate Resistance	T <sub>A</sub> = 25°C	Q1		0.6		Ω
			Q2		0.6		1
WITCHIN	G CHARACTERISTICS						
td <sub>(ON)</sub>	Turn-On Delay Time	Q1:	Q1		8		ns
		$V_{DD} = 40 \text{ V}, I_{D} = 7.8 \text{ A},$ $R_{GEN} = 6 \Omega$	Q2		8		
t <sub>r</sub>	Rise Time	Q2:	Q1		2		ns
		$V_{DD} = 40 \text{ V}, I_D = 7.8 \text{ A},$	Q2		2		
t <sub>D(OFF)</sub>	Turn-Off Delay Time	$R_{GEN} = 6 \Omega$	Q1		12		ns
			Q2		12		
t <sub>f</sub>	Fall Time		Q1		3		ns
			Q2		3		
Qg	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V	Q1		8.4		nC
			Q2		8.4		
Qg	Total Gate Charge	V <sub>GS</sub> = 0 V to 6 V	Q1		5.5		nC
-		Q1:	Q2		5.5		1
Q <sub>gs</sub>	Gate-to-Source Gate Charge	$V_{DD} = 40 \text{ V},$	Q1		2.5		nC
3-		I <sub>D</sub> = 7.8 A Q2:	Q2		2.5		1
Q <sub>gd</sub>	Gate-to-Drain "Miller" Charge	$V_{DD} = 40 \text{ V},$	Q1		1.8		nC
⊸gu		I <sub>D</sub> = 7.8 A					
			Q2		1.8		

# ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25°C unless otherwise noted)

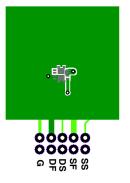
Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
DRAIN-SC	OURCE DIODE CHARACTERISTICS						
$V_{SD}$	Source-to-Drain Diode Forward Volt-	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 7.8 A (Note 2)	Q1		0.82	1.5	V
	age	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 7.8 A (Note 2)	Q2		0.82	1.5	
t <sub>rr</sub>	Reverse Recovery Time	Q1:	Q1		31		ns
		I <sub>F</sub> = 7.8 A, di/dt = 300 A/μs Q2:	Q2		31		
Q <sub>rr</sub>	Reverse Recovery Charge	I <sub>F</sub> = 7.8 A, di/dt = 300 A/μs	Q1		33		nC
			Q2		33		
t <sub>rr</sub>	Reverse Recovery Time	Q1:	Q1		13		ns
		I <sub>F</sub> = 7.8 A, di/dt = 1000 A/μs - Q2:	Q2		13		
Q <sub>rr</sub>	Reverse Recovery Charge	l <sub>F</sub> = 7.8 A, di/dt = 1000 A/μs	Q1		88		nC
		,	Q2		88		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

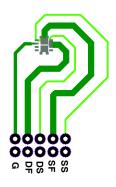
1.  $R_{\theta JA}$  is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5  $\times$  1.5 in. board of FR-4 material.  $R_{\theta CA}$  is determined by the user's board design.



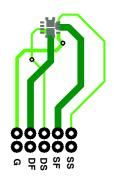
a) 70°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b) 70°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



c) 135°C/W when mounted on a minimum pad of 2 oz copper.



d) 135°C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%.
- Q1: E<sub>AS</sub> of 31 mJ is based on starting T<sub>J</sub> = 25°C; N-ch: L = 1 mH, I<sub>AS</sub> = 7.9 A, V<sub>DD</sub> = 80 V, V<sub>GS</sub> = 15 V. 100% test at L = 1 mH, I<sub>AS</sub> = 8 A. Q2: E<sub>AS</sub> of 31 mJ is based on starting T<sub>J</sub> = 25°C; N-ch: L = 1 mH, I<sub>AS</sub> = 7.9 A, V<sub>DD</sub> = 80 V, V<sub>GS</sub> = 15 V. 100% test at L = 1 mH, I<sub>AS</sub> = 8 A.
   Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal
- & electro-mechanical application board design.

# **TYPICAL CHARACTERISTICS**

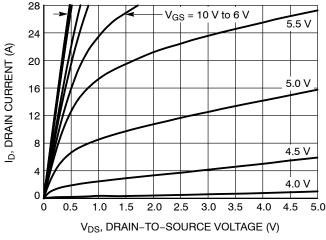


Figure 1. On-Region Characteristics

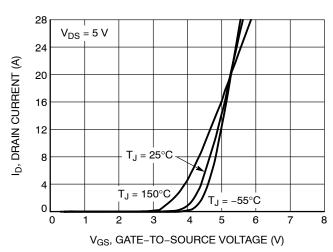


Figure 2. Transfer Characteristics

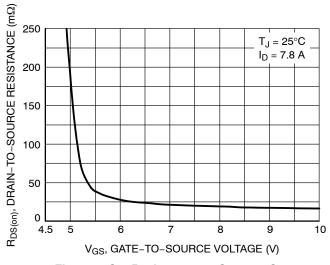


Figure 3. On-Resistance vs. Gate-to-Source Voltage

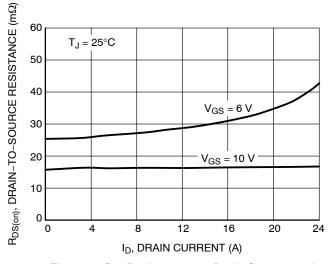


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

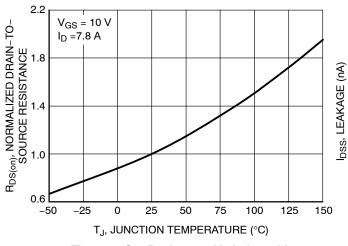


Figure 5. On–Resistance Variation with Temperature

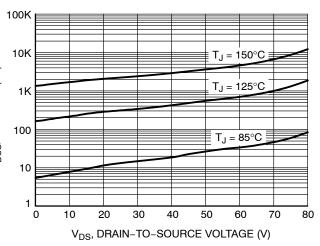


Figure 6. Drain-to-Source Leakage Current vs. Voltage

# **TYPICAL CHARACTERISTICS**

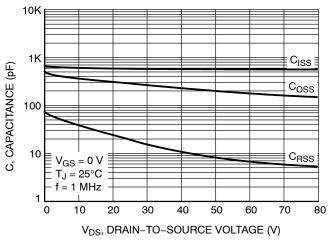


Figure 7. Capacitance Variation

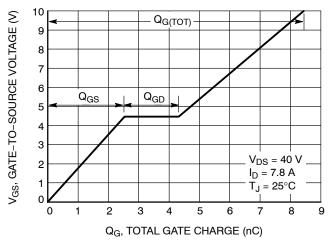


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

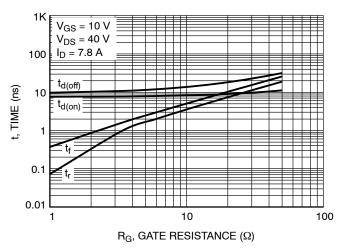


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

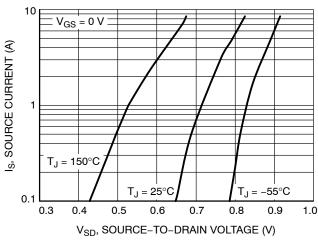


Figure 10. Diode Forward Voltage vs. Current

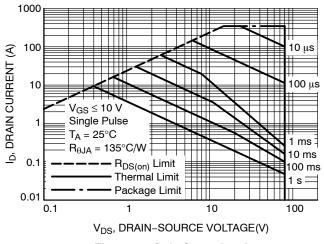


Figure 11. Safe Operating Area

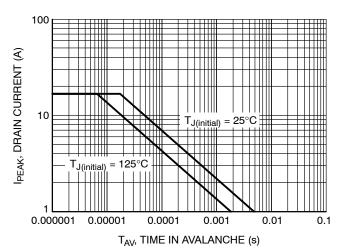


Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

# **TYPICAL CHARACTERISTICS**

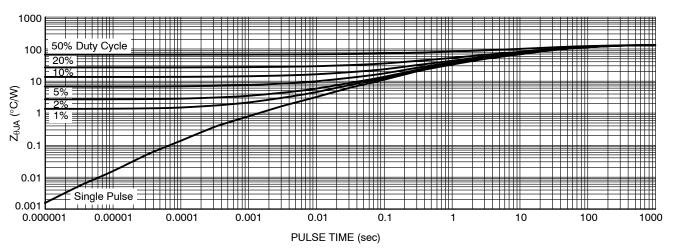


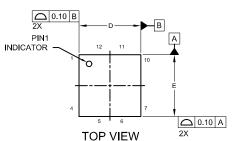
Figure 13. Thermal Characteristics





# WQFN12 3.3X3.3, 0.65P CASE 510CJ **ISSUE A**

**DATE 08 AUG 2022** 



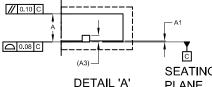
FRONT VIEW

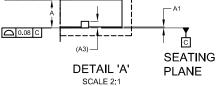
#### NOTES:

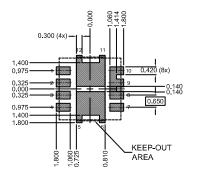
SEE

**DETAIL A** 

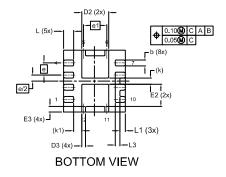
- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- CONTROLLING DIMENSION: MILLIMETERS
- COPLANARITY APPLIES TO THE EXPOSED
- 4. SEATING PLANE IS DEFINED BY THE TERMINALS. "A1" IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.
- 5. IT IS RECOMMENDED TO HAVE NO TRACES OR VIAS WITHIN THE KEEP OUT AREA.







MILLIMETERS DIM MIN NOM MAX 0.70 0.75 0.80 Α 0.00 A1 0.05 АЗ 0.20 REF 0.27 0.32 0.37 b D 3.30 3.40 3.20 D2 1.34 1.44 1.54 D3 0.10 0.20 0.30 Ε 3.20 3.30 3.40 1.09 1.29 F2 1.19 E3 0.20 0.30 0.40 е 0.65 BSC 0.325 BSC e/2 1.24 BSC е1 k 0.33 REF k1 0.43 REF 0.44 0.54 L 0.64 L1 0.19 0.29 0.39 L3 0.15 0.25 0.35



# **GENERIC MARKING DIAGRAM\***



XXXX = Specific Device Code = Assembly Location = Year

WW = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "", may or may not be present. Some products may not follow the Generic Marking.

LAND PATTERN
RECOMMENDATION
*FOR ADDITIONAL INFORMATION ON OUF
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DETAILS, PLEASE DOWNLOAD THE ON
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MANUAL, SOLDERRM/D.

DOCUMENT NUMBER: 98AON13806G Electronic versions are uncontrolled except when accessed directly from the Printed versions are uncontrolled except when stamped "CONTROLLED CONTROLLED CONTROLLED CONTROLLED CONTROLLED CONTRO			
DESCRIPTION:	WQFN12 3.3X3.3, 0.65P		PAGE 1 OF 1

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